

iMiD 2025

The 25th International Meeting on Information Display
August 19-22, 2025 / BEXCO, BUSAN, KOREA

Session Title:	31. Metrology and Inspection
Session Date:	August 21 (Thu.), 2025
Session Time:	11:00-12:45
Session Room:	Room G (314~315)
Session Chair(s):	Dr. Yong Jun Park (Samsung Display Co., Ltd., Korea) Prof. Min Young Kim (Kyungpook Nat'l Univ., Korea)

[G31-1] [Invited]	11:00-11:25
--------------------------	--------------------

Acousto-Optic Tunable Filter-Based Hyperspectral Imaging Method for Detecting Manufacturing Issues in Display Panel Production

Jonghee Yoon (Ajou Univ., Korea), Sanghoon Lee, and Taehoon Kim (Green Optics Co., Ltd., Korea)

[G31-2] [Invited]	11:25-11:50
--------------------------	--------------------

Tantium MicroLED: Redefining Performance and Efficiency in Next-Generation Displays

Ying-Tsang Liu, Kuan-Yung Liao, Ching-Liang Lin, Sheng-Yuan Sun, and Yun-Li Li (PlayNitride Inc., Taiwan)

[G31-3] [Invited]	11:50-12:15
--------------------------	--------------------

Recent AOI Techniques with Deep-Learning for Advanced Display Industries

Min Young Kim (Kyungpook Nat'l Univ., Korea)

[G31-4]	12:15-12:30
----------------	--------------------

Layer-Resolved Measurement of Thickness and Refractive Index in a Triple-Layer Protective Film Using Spectral Interference Method

Jungjae Park, Jaeseok Bae, and Jonghan Jin (Meter-Lab. Inc., Korea)

[G31-5]	12:30-12:45
----------------	--------------------

Precision Topography Metrology Using White Light Scanning Interferometry with Vibration Tolerance

Chan Young Park, Ohchul Shin, SungYup An, Hyobin Jeong, and Jonghoon Kim (HB Solution Co., Ltd., Korea)